


<b>Search Notes</b> 	<b>Application/Control No.</b> 10058173	<b>Applicant(s)/Patent Under Reexamination</b> STEFANIK ET AL.
	<b>Examiner</b> Zhen, Li B	<b>Art Unit</b> 2194

### SEARCHED

Class	Subclass	Date	Examiner
717	171,172,173,177	6/27/2007	LZ
update	search	12/4/07	LZ
update	search	6/10/2008	LZ
update	search	11/26/2008	LZ
update	search	5/15/2009	LZ

### SEARCH NOTES

Search Notes	Date	Examiner
EAST (US-PGPUB;USPAT;USOCR;EPO;DERWENT;IBMTDB) See search history printout	6/27/2007	LZ
Inventor Name Search	6/27/2007	LZ
EAST (US-PGPUB;USPAT;USOCR;EPO;DERWENT;IBMTDB) See search history printout	12/4/07	LZ
EAST (US-PGPUB;USPAT;USOCR;EPO;DERWENT;IBMTDB) See search history printout	6/10/2008	LZ
EAST (US-PGPUB;USPAT;USOCR;EPO;DERWENT;IBMTDB) See search history printout	11/26/2008	LZ
EAST (US-PGPUB;USPAT;USOCR;EPO;DERWENT;IBMTDB) See search history printout	5/15/2009	LZ

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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